

Data Sheet September 1998 File Number 481.4

General Purpose High Current NPN Transistor Array

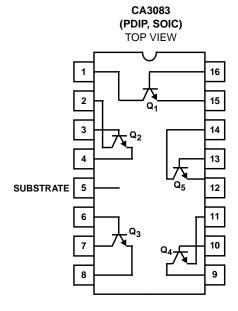
The CA3083 is a versatile array of five high current (to 100mA) NPN transistors on a common monolithic substrate. In addition, two of these transistors (Q_1 and Q_2) are matched at low current (i.e., 1mA) for applications in which offset parameters are of special importance.

Independent connections for each transistor plus a separate terminal for the substrate permit maximum flexibility in circuit design.

Ordering Information

PART NUMBER (BRAND)	TEMP. RANGE (°C)	PACKAGE	PKG. NO.	
CA3083	-55 to 125	16 Ld PDIP	E16.3	
CA3083M (3083)	-55 to 125	16 Ld SOIC	M16.15	
CA3083M96 (3083)	-55 to 125	16 Ld SOIC Tape and Reel	M16.15	

Pinout



Features

•	High I _C	100mA	(Max)
•	Low V _{CE sat} (at 50mA)	. 0.7V	(Max)
•	Matched Pair (Q ₁ and Q ₂)		
	- V _{IO} (V _{BE} Match)	±5mV	(Max)
	- I _{IO} (at 1mA)	2.5μΑ	(Max)

 5 Independent Transistors Plus Separate Substrate Connection

Applications

- Signal Processing and Switching Systems Operating from DC to VHF
- · Lamp and Relay Driver
- · Differential Amplifier
- Temperature Compensated Amplifier
- · Thyristor Firing
- See Application Note AN5296 "Applications of the CA3018 Circuit Transistor Array" for Suggested Applications

CA3083

Absolute Maximum Ratings

Thermal Information

Thermal Resistance (Typical, Note 2)	θ_{JA} (oC/W)	θ_{JC} (oC/W)
PDIP Package	135	N/A
SOIC Package		N/A
Maximum Power Dissipation (Any One Tra	nsistor)	500mW
Maximum Junction Temperature (Plastic P	ackage)	150°C
Maximum Storage Temperature Range	65	OC to 150°C
Maximum Lead Temperature (Soldering 10	Os)	300°C
(SOIC - Lead Tips Only)		

Operating Conditions

Temperature Range -55°C to 125°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES:

- 1. The collector of each transistor of the CA3083 is isolated from the substrate by an integral diode. The substrate must be connected to a voltage which is more negative than any collector voltage in order to maintain isolation between transistors and provide normal transistor action. To avoid undesired coupling between transistors, the substrate Terminal (5) should be maintained at either DC or signal (AC) ground. A suitable bypass capacitor can be used to establish a signal ground.
- 2. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications For Equipment Design, $T_A = 25^{\circ}C$

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
FOR EACH TRANSISTOR	•	'				'	
Collector-to-Base Breakdown Voltage	V _{(BR)CBO}	$I_C = 100\mu A, I_E = 0$		20	60	-	V
Collector-to-Emitter Breakdown Voltage	V _{(BR)CEO}	$I_C = 1 \text{mA}, I_B = 0$		15	24	-	V
Collector-to-Substrate Breakdown Voltage	V _{(BR)CIO}	$I_{CI} = 100 \mu A, I_B = 0, I_E = 0$		20	60	-	V
Emitter-to-Base Breakdown Voltage	V _{(BR)EBO}	I _E = 500μA, I _C = 0		5	6.9	-	V
Collector-Cutoff-Current	I _{CEO}	V _{CE} = 10V, I _B = 0		-	-	10	μΑ
Collector-Cutoff-Current	I _{CBO}	V _{CB} = 10V, I _E = 0		-	-	1	μΑ
DC Forward-Current Transfer Ratio (Note 3) (Figure 1)	h _{FE}	V _{CE} = 3V	I _C = 10mA	40	76	-	
			I _C = 50mA	40	75	-	
Base-to-Emitter Voltage (Figure 2)	V _{BE}	V _{CE} = 3V, I _C = 10mA		0.65	0.74	0.85	V
Collector-to-Emitter Saturation Voltage (Figures 3, 4)	V _{CE} SAT	I _C = 50mA, I _B = 5mA		-	0.40	0.70	V
Gain Bandwidth Product	f _T	V _{CE} = 3V, I _C = 10mA		-	450	-	MHz
FOR TRANSISTORS Q ₁ AND Q ₂ (As a Differential An	nplifier)	1				1	1
Absolute Input Offset Voltage (Figure 6)	IVIOI	V _{CE} = 3V, I _C = 1mA		-	1.2	5	mV
Absolute Input Offset Current (Figure 7)	I _{IO}	V _{CE} = 3V, I _C = 1mA		-	0.7	2.5	μΑ

NOTE:

3. Actual forcing current is via the emitter for this test.

Typical Performance Curves

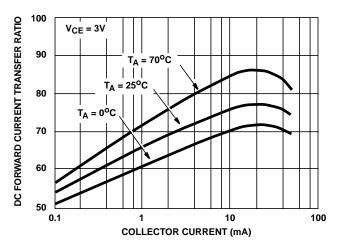


FIGURE 1. hFE vs IC

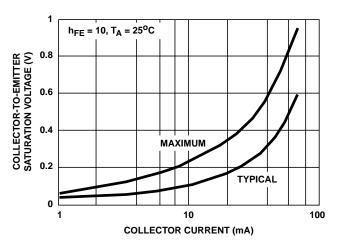


FIGURE 3. $V_{CE\ SAT}$ vs I_{C}

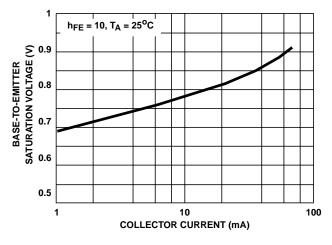


FIGURE 5. $V_{BE\ SAT}$ vs I_{C}

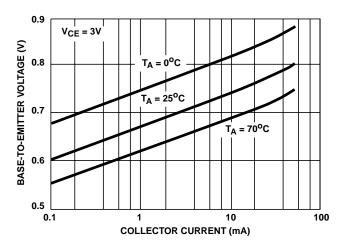


FIGURE 2. V_{BE} vs I_C

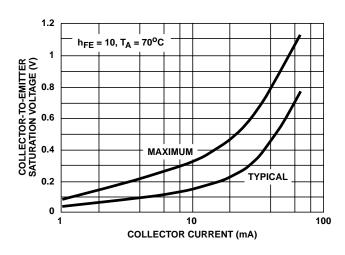


FIGURE 4. V_{CE SAT} vs I_C

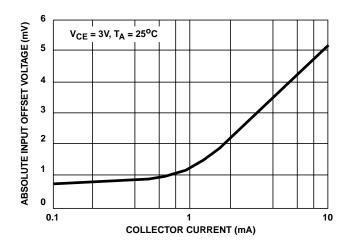


FIGURE 6. V_{IO} vs I_C (TRANSISTORS Q_1 AND Q_2 AS A DIFFERENTIAL AMPLIFIER)

Typical Performance Curves (Continued)

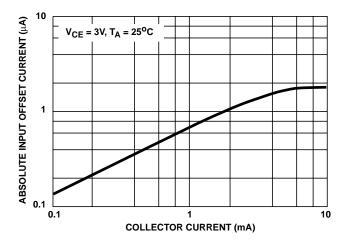


FIGURE 7. I_{IO} vs I_C (TRANSISTORS Q₁ AND Q₂ AS A DIFFERENTIAL AMPLIFIER)

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